

Appl. No. 09/871,596  
Amdt. Dated July 26, 2004  
Reply to Office Action of March 24, 2004

Attorney Docket No. 81754.0061  
Customer No.: 26021

**Amendments to the Claims:**

This listing of claims will replace all prior versions, and listings, of claims in the application:

**Listing of Claims:**

1. (Currently Amended) A method for testing a physical layer device including a link layer interface, a physical layer logic circuit to be connected to said link layer interface, and a plurality of ports to be connected to said physical layer logic circuit are provided beforehand in said physical layer device;

in testing, ~~said~~ test link layer circuit is connected to said physical layer logic circuit through said link layer interface, and ~~said~~ test physical layer logic circuit is connected to a first port that is one of said plurality of ports, and said first port is connected to a second port that is one of said plurality of ports through an external bus, and the second port is connected to said physical layer logic circuit; and

~~said~~ link layer interface, ~~said~~ physical layer logic circuit, and ~~said~~ plurality of ports are tested.

2. (Currently Amended): A physical layer device with test circuits, ~~said~~ physical layer device including a link layer interface, a physical layer logic circuit to be connected to ~~said~~ link layer interface, and a plurality of ports to be connected to ~~said~~ physical layer logic circuit, ~~said~~ physical layer device characterized by ~~eompromising comprising~~:

a test link layer circuit for establishing,[[,]] in testing, a connection with ~~said~~ link layer interface, a connection with ~~said~~ physical layer logic circuit through ~~said~~ link layer interface and communicating predetermined data with ~~said~~ physical layer logic circuit; and

Appl. No. 09/871,596  
Amdt. Dated July 26, 2004  
Reply to Office Action of March 24, 2004

Attorney Docket No. 81754.0061  
Customer No.: 26021

a test physical layer logic circuit for establishing, in testing, a connection with said plurality of ports, wherein a first port that is one of said plurality of ports, is connected to a second port that is one of said plurality of ports through an external bus, ~~where and the first and second ports are connected to a connection with said physical layer logic circuit through said plurality of ports and communicating predetermined data with said physical layer logic circuit.~~

3. (Original) A physical layer device with test circuits according to claim 2, characterized in that:

    said link layer interface includes a switch for selectively establishing a connection with an external link layer device or said test link layer circuit; and

    a predetermined port from among said plurality of ports includes a switch for selectively establishing a connection with said physical layer logic circuit or said test physical layer logic circuit.

4-13. (Canceled)